Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/764,756	TZOU, HON-DER		
Examiner	Art Unit		
HUY T. NGUYEN	2616		

SEARCHED							
Class	Subclass	Date	Examiner				
386 84 725 J	46 95 125 126 609 100	6/24/03	-BW				

INTERFERENCE SEARCHED			SEARCHED		
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INSTERRAL US PEPUB US PAT, USOCR, FPO TPO, DERWENT, IBM (See printont)	6/24/03 5/21/03	- be		
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